

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10541940	LEE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Guadalupe McCall, Yaritza	2859

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
33	755, 758, 768	8/15/07	YGM

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
33 / 755, 758, 768	8/15/07	YGM

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>